

Notice of References Cited

Application/Control No.

10/090,653

Applicant(s)/Patent Under
Reexamination
YAVID ET AL.

Examiner

D. I. Lee

Art Unit

2876

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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